

試験報告書番号: Test report no.:	JP263MLX 001	申請受理番号: Order no.:	P02373024 (150329631)	頁 1 / 12 Page 1 / 12
申請者参照番号: Client reference no.:	N / A	申請日: Order date	2026-07-02	
申請者: Client:	FUJITSU LIMITED 1-5, Omiya-cho, Saiwai-ku, Kawasaki City, Kanagawa, 212-0014, Japan			
試験品: Test item:	VEN			
識別表示: / 型名: Identification / Type no.:	ReEra / 1.0			
申請内容: Order content:	OpenADR Certification Test (Pickup test for similar products)			
適用した試験基準: Test specification:	OpenADR 2.0b Certification Test Specification Version 1.1.7			
サンプル受理日: Date of sample receipt:	N/A	No product photo		
サンプル番号: Test sample no:	N/A			
試験期間: Testing period:	2026-07-21			
試験場所: Place of testing:	TÜV Rheinland Japan Ltd. GTAC 4-25-2 Kita-Yamata, Tsuzuki-ku Yokohama 224-0021, Japan			
試験所: Testing laboratory:	TÜV Rheinland Japan Ltd.			
試験結果*: Test result*:	適合 / Pass			
試験者: tested by:	照査者: authorized by:			
日付: 2026-07-27 Date:	発行日: 2026-07-27 Issue Date:			
職位 / Position:	専門家 / Expert	職位 / Position:	専門家 / Expert	
備考 / Other:	A pickup test was performed because the customer declared that "ReEra / 1.0" was a similar product to the "Fujitsu Intelligent Society Solution Distributed Energy Management solution OpenADR VEN module 2.0b / 1.0". The standard test report is JP21RNEY-002.			
納品時の試験品の状態: Condition of the test item at delivery:	試験品は完全で破損はない Test item complete and undamaged			
* 凡例: * Legend:	P(ass) = 適合 P(ass) = passed a.m. test specification(s)	F(ail) = 不適合 F(ail) = failed a.m. test specification(s)	N/A = 適用外 N/A = not applicable	N/T = 試験せず N/T = not tested
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備考
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1 General Product Information

1.1 Client Information

Company Name:	see page 1
Address:	see page 1
Contact Person:	Yuichiro Tanaka / Etsuko Katou
Phone:	+ 81-44-331-1111 / + 81-44-331-1111
E-mail:	tanaka-yuichiro@fujitsu.com / eh-kato@fujitsu.com

1.2 General SUT Information

The system under test is software implementation of OpenADR protocol installed on Cloud.

Serial Number:	N/A
Hardware Version:	N/A
Firmware version:	1.0

1.3 General EUT Description

Equipment under test:	see page 1
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1.4 Profile

Product type:	VEN
OpenADR profile:	2.0b
Mode:	Pull, Push
Transport:	Simple HTTP, XMPP
Security:	Standard Security

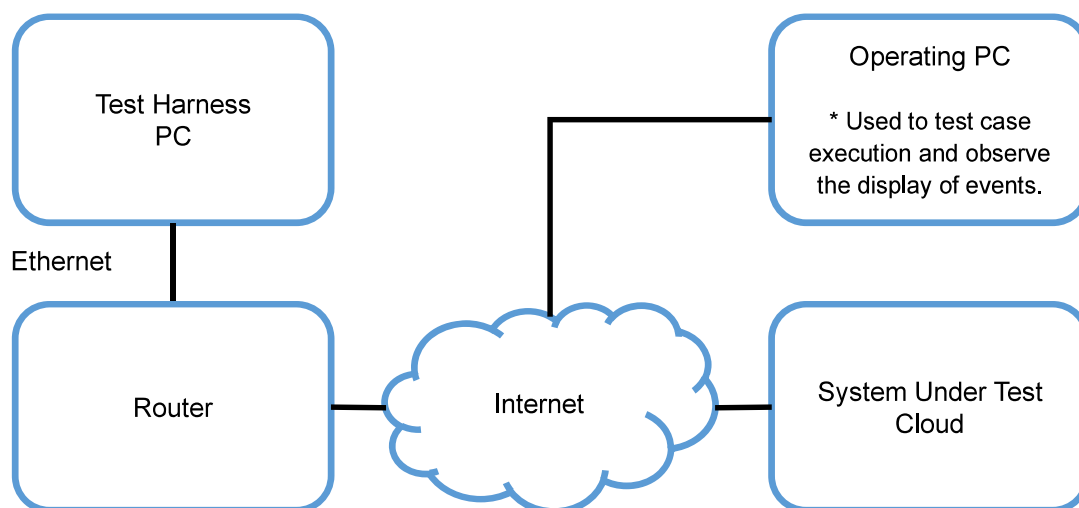
2 Testing Laboratory

see page 1

2.1 Test Equipment

Equipment ID	Model Product name	Manufacture	Category	Version
G1800528	OpenADR Test Harness for 2.0b	QualityLogic	Software	1.1.7

2.2 Test Setup



3 Information about Test Results

3.1 General

Documentation of tested devices and results:

The complete set of measurement results is stored at the TÜV Rheinland Japan Ltd. test laboratory and is available on demand.

Interpretation of test results:

The results of the inspection are described on the following pages. "Pass" in the test result list of this test report means the performed test according to the test specification was verified and that the tested device is conformant to the specification. "Fail" means that the performed test according to the test specification was verified and the tested device is not conformant to the specification or that test didn't run to completion because the tested device is not conformant to the specification. "N/A" means the test cases are optional and/or not applicable to the tested device.

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4 Test Results

4.1 VEN Pull Pickup Tests

4.1.1 EiRegisterParty Service

No.	Test Case Name	Date	Result
01	N1_0020_TH_VTN_1	Jul 21 2026	PASS
02	N1_0030_TH_VTN_1	Jul 21 2026	PASS
03	N1_0040_TH_VTN_1	Jul 21 2026	PASS

4.1.2 EiOpt Service

No.	Test Case Name	Date	Result
01	P1_2020_TH_VTN_1(*)	Jul 21 2026	PASS
02	P1_2040_TH_VTN_1	Jul 21 2026	PASS

(*) See "5 Remarks and References"

4.1.3 EiReport Service

No.	Test Case Name	Date	Result
01	R1_3030_TH_VTN_1	Jul 21 2026	PASS
02	R1_3040_TH_VTN_1	Jul 21 2026	PASS
03	R1_3045_TH_VTN_1	Jul 21 2026	PASS
04	R1_3160_TH_VTN_1	Jul 21 2026	PASS
05	R1_3170_TH_VTN_1	Jul 21 2026	PASS
06	R1_3180_TH_VTN_1	Jul 21 2026	PASS

4.1.4 EiEvent Service

No.	Test Case Name	Date	Result
01	E1_1020_TH_VTN_1(*)	Jul 21 2026	PASS
02	E1_1025_TH_VTN_1	Jul 21 2026	PASS
03	E1_1030_TH_VTN_1	Jul 21 2026	PASS
04	E1_1055_TH_VTN_1	Jul 21 2026	PASS
05	E1_1060_TH_VTN_1	Jul 21 2026	PASS
06	E1_1090_TH_VTN_1	Jul 21 2026	PASS

(*) See "5 Remarks and References"

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4.1.5 EiEvent Ported A Profile

No.	Test Case Name	Date	Result
01	A_E1_0180_TH_VTN_1	Jul 21 2026	PASS
02	A_E1_0262_TH_VTN_1	Jul 21 2026	PASS
03	A_E1_0267_TH_VTN_1	Jul 21 2026	PASS
04	A_E1_0270_TH_VTN_1	Jul 21 2026	PASS

4.1.6 General Tests

No.	Test Case Name	Date	Result
01	G1_4005_TH_VTN_1	Jul 21 2026	PASS
02	G1_4007_TH_VTN_1	Jul 21 2026	PASS
03	G1_4010_TH_VTN_1	Jul 21 2026	PASS
04	G1_4030_TH_VTN_1	Jul 21 2026	PASS

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4.2 VEN Push Pickup Tests

4.2.1 EiRegisterParty Service

No.	Test Case Name	Date	Result
01	N0_5020_TH_VTN_1	Jul 21 2026	PASS
02	N0_5030_TH_VTN_1	Jul 21 2026	PASS
03	N0_5040_TH_VTN	Jul 21 2026	PASS

4.2.2 EiOpt Service

No.	Test Case Name	Date	Result
01	P0_7020_TH_VTN_1(*)	Jul 21 2026	PASS
02	P0_7040_TH_VTN_1	Jul 21 2026	PASS

(*) See "5 Remarks and References"

4.2.3 EiReport Service

No.	Test Case Name	Date	Result
01	R0_8030_TH_VTN	Jul 21 2026	PASS
02	R0_8040_TH_VTN	Jul 21 2026	PASS
03	R0_8045_TH_VTN	Jul 21 2026	PASS
04	R0_8160_TH_VTN	Jul 21 2026	PASS
05	R0_8170_TH_VTN	Jul 21 2026	PASS
06	R0_8180_TH_VTN	Jul 21 2026	PASS

4.2.4 EiEvent Service

No.	Test Case Name	Date	Result
01	E0_6020_TH_VTN(*)	Jul 21 2026	PASS
02	E0_6025_TH_VTN	Jul 21 2026	PASS
03	E0_6030_TH_VTN	Jul 21 2026	PASS
04	E0_6055_TH_VTN	Jul 21 2026	PASS
05	E0_6060_TH_VTN	Jul 21 2026	PASS
06	E0_6090_TH_VTN	Jul 21 2026	PASS

(*) See "5 Remarks and References"

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4.2.5 EiEvent Ported A Profile

No.	Test Case Name	Date	Result
01	A_E0_0180_TH_VTN_1	Jul 21 2026	PASS
02	A_E0_0262_TH_VTN_1	Jul 21 2026	PASS
03	A_E0_0267_TH_VTN_1	Jul 21 2026	PASS
04	A_E0_0270_TH_VTN_1	Jul 21 2026	PASS

4.2.6 General Tests

No.	Test Case Name	Date	Result
01	G0_9005_TH_VTN	Jul 21 2026	PASS
02	G0_9010_TH_VTN	Jul 21 2026	PASS
03	G0_9030_TH_VTN	Jul 21 2026	PASS

4.2.7 XMPP Tests

No.	Test Case Name	Date	Result
01	N0_5020_TH_VTN_1	Jul 21 2026	PASS
02	N0_5030_TH_VTN_1	Jul 21 2026	PASS
03	P0_7040_TH_VTN_1	Jul 21 2026	PASS
04	R0_8030_TH_VTN	Jul 21 2026	PASS
05	E0_6030_TH_VTN	Jul 21 2026	PASS
06	G0_9005_TH_VTN	Jul 21 2026	PASS
07	G0_9010_TH_VTN	Jul 21 2026	PASS

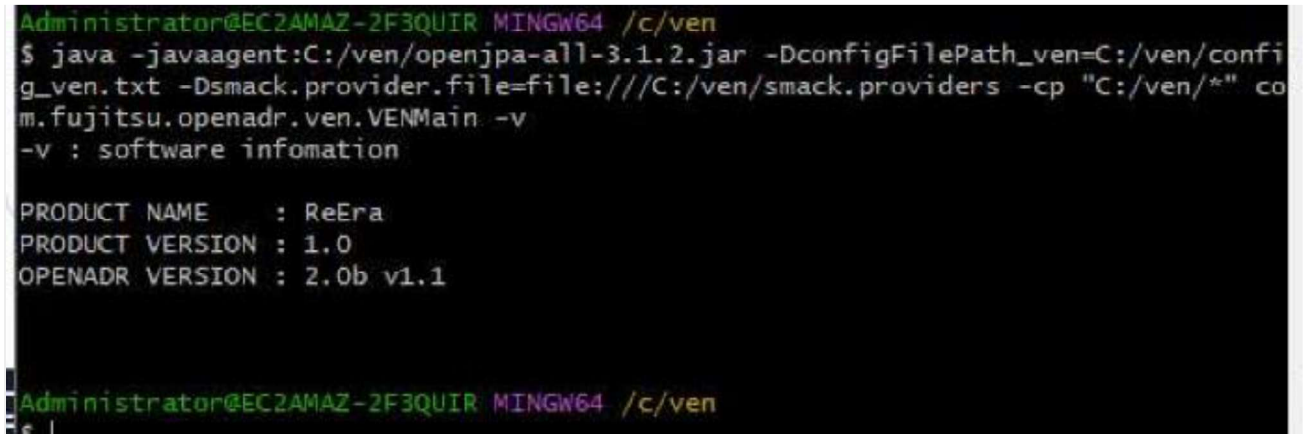
5 Remarks and References

Test Items (P0_7020, P1_2020, E0_6020, E1_1020) are tested in G0_9030 / G1_4030. (not tested separately)

Log files for the executed test cases are provided in the electronic format.

List of all executed tests with links to the log files is located in the "logfile.html" which could be opened in any web-browser.

6 Photos



```
Administrator@EC2AMAZ-2F3QUIR MINGW64 /c/ven
$ java -javaagent:C:/ven/openjpa-all-3.1.2.jar -DconfigFilePath_ven=C:/ven/confi
g_ven.txt -Dsmack.provider.file=file:///C:/ven/smack.providers -cp "C:/ven/*" co
m.fujitsu.openadr.ven.VENMain -v
-v : software infomation

PRODUCT NAME      : ReEra
PRODUCT VERSION   : 1.0
OPENADR VERSION   : 2.0b v1.1

Administrator@EC2AMAZ-2F3QUIR MINGW64 /c/ven
$
```

Photo 1: System screen capture (Product Information)